

**Search Notes**

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Examiner

Christopher H. Yaen

Applicant(s)/Patent under  
Reexamination

LIOUBIN ET AL.

Art Unit

1642

**SEARCHED**

Class	Subclass	Date	Examiner
Updated		3/10/2005	CHY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
435	7.1	3/15/2005	CHY
stic seq search SEQ ID No: 2		3/15/2005	CHY

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated searches	3/10/2005	CHY
STIC seq search SEQ ID No: 2	3/10/2005	CHY